

PTO/SB/08A (08-00)

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Complete If Known Substitute for Form 1449A/PTO **Application Number** Filing Date 08/02/01 INFORMATION DISCLOSURE Sudhir K. Madan First Named Inventor STATEMENT BY APPLICANT Group Art Unit TBD **Examiner Name** TBD (use as many sheets as necessary) TI-30841 Attorney Docket No.

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DV	CA	"Highly Scalable and Fully Logic Compatible SRAM Cell Technology with Metal Damascene Process and W Local Interconnect," 0-7803-4700-6/98; 1998 IEEE; by M. Inohara, H. Oyamastu, Y Unno, Y FuKaura, S. Goto, Y. Egi, and M. Kinugawa.	
DV	СВ	"A Novel 6.4μm ² Full-CMOS SRAM Cell with Aspect Ratio of 0.63 in a High-Performance 0.25 μm-Generation CMOS Technology"; 0-7803-4700-6/98; 1998 IEEE; by K. J. Kim, J. M. Younn, S. B. Kim, J. H. Kim, S. H. Hwang, K. T. Kim, and Y. S. Shin.	
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